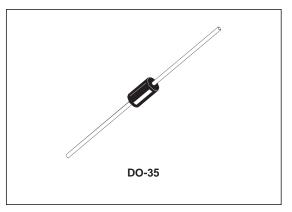


BAT46

SMALL SIGNAL SCHOTTKY DIODE



DESCRIPTION

General purpose, metalto silicon diode featuring high breakdown voltage low turn-on voltage.

ABSOLUTE RATINGS (limiting values)

Symbol	Parameter	Value	Unit		
V _{RRM}	Repetitive Peak Reverse Voltage		100	V	
l _F	Forward Continuous Current*	$T_a = 25^{\circ}C$	150	mA	
I _{FRM}	Repetitive Peak Forward Current*	prward Current* $ \begin{array}{c} t_p \leq \text{1s} \\ \delta \leq 0.5 \end{array} $		mA	
I _{FSM}	Surge non Repetitive Forward Current*	$t_p = 10ms$	750	mA	
P _{tot}	Power Dissipation*	$T_I = 80^{\circ}C$	150	mW	
T _{stg} Tj	Storage and Junction Temperature Range		- 65 to + 150 - 65 to + 125	°C	
TL	Maximum Temperature for Soldering during 10 Case	230	°C		

THERMAL RESISTANCE

Symbol	Test Conditions	Value	Unit	
R _{th(j-a)}	Junction-ambient*	300	°C/W	

* On infinite heatsink with 4mm lead length.

BAT46

ELECTRICAL CHARACTERISTICS

STATIC CHARACTERISTICS

Symbol	Test Conditions		Min.	Тур.	Max.	Unit
V _{BR}	$T_j = 25^{\circ}C$	I _R = 100μA	100			V
VF *	$T_j = 25^{\circ}C$	I _F = 0.1mA			0.25	V
	$T_j = 25^{\circ}C$	I _F = 10mA			0.45	
	$T_j = 25^{\circ}C$	I _F = 250mA			1	
I _R *	$T_j = 25^{\circ}C$	V _R = 1.5V			0.5	μΑ
	$T_j = 60^{\circ}C$				5	
	$T_j = 25^{\circ}C$	V _R = 10V			0.8	
	$T_j = 60^{\circ}C$				7.5	
	$T_j = 25^{\circ}C$	$V_R = 50V$			2	
	$T_j = 60^{\circ}C$				15	
	$T_j = 25^{\circ}C$	V _R = 75V			5]
	$T_j = 60^{\circ}C$				20	

DYNAMIC CHARACTERISTICS

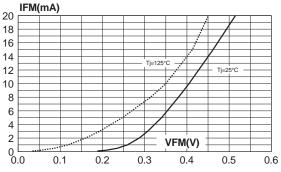
	Symbol	Test Conditions			Min.	Тур.	Max.	Unit
ſ	0	T _j = 25°C	$V_R = 0V$	f = 1Mhz		10		рF
С	T _j = 25°C	$V_R = 1V$	1 - 110112		6			

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* Pulse test: $t_p \! \leq \! 300 \mu s \ \delta \! < \! 2 \%$.

Fig. 1-1: Forward voltage drop versus forward current (low level, typical values)

IFM(A)



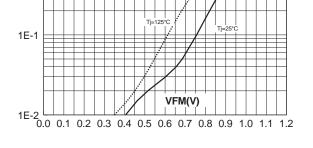


Fig. 1-2: Forward voltage drop versus forward cur-

Fig. 2: Leakage current versus reverse voltage applied (typical values)

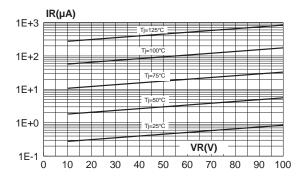
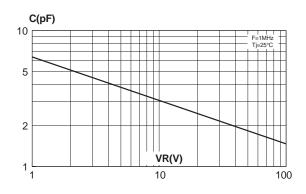
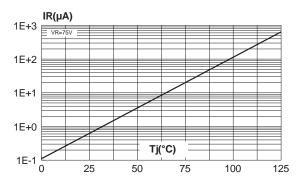


Fig. 4: Junction capacitance versus reverse voltage applied (typical values)

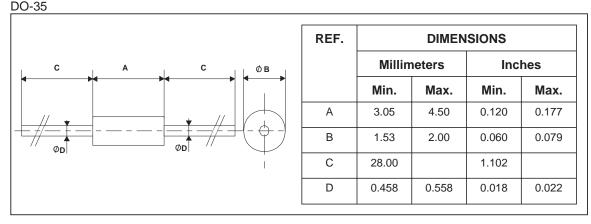


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Fig. 3: Leakage current versus junction temperature (typical values)



PACKAGE MECHANICAL DATA



- Cooling method: by convection and conduction
- Marking: clear, ring at cathode end
- Weight: 0.15g

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